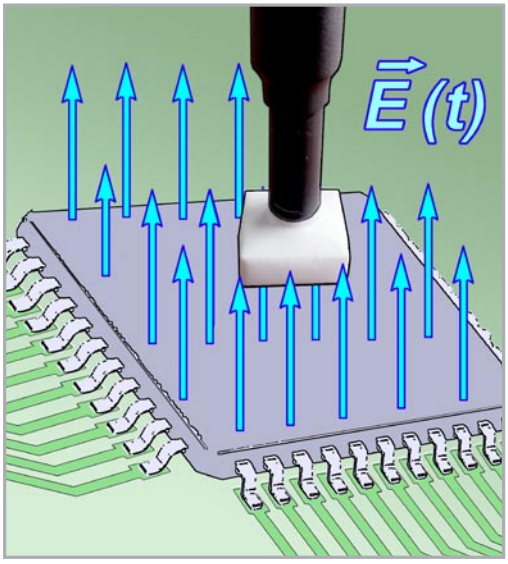

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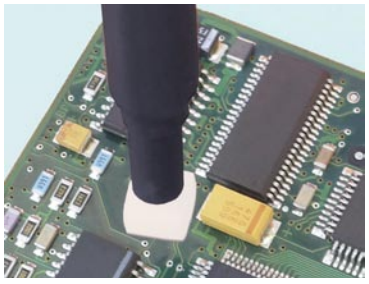
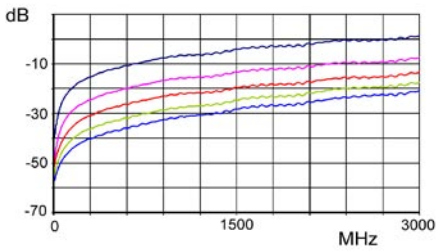
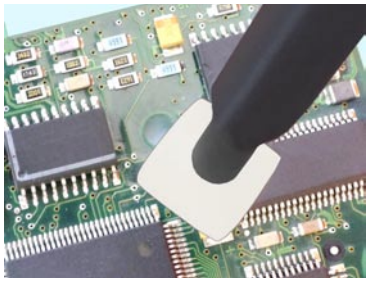
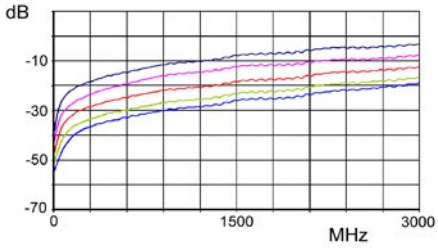
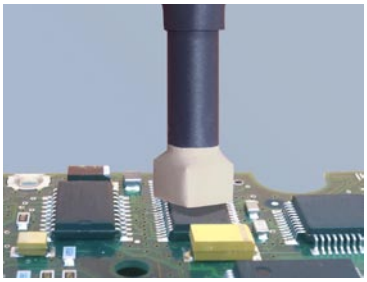
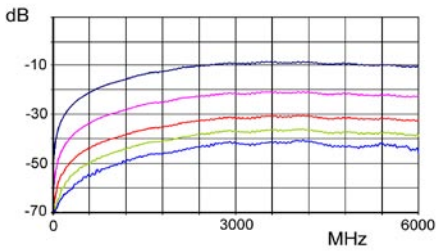
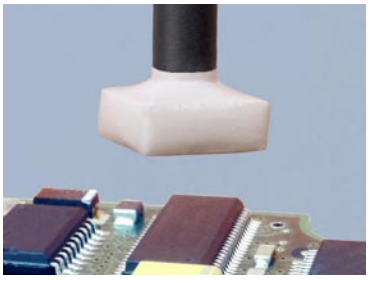
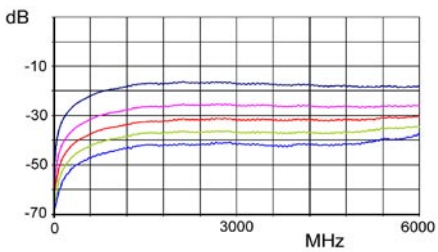
Brief description

Disturbances are emitted if an electronic module generates an electric field and this field leaves the module. Four sensitive, passive E near-field probes have been developed to clarify this EMC phenomenon. They can be used at a distance of around 1 cm to the module and operated via the 50 ohm input of a spectrum analyzer. Their sheath current is attenuated.
The probes' frequency response was measured above an E-field source of 1 x 1 mm² at a distance of - 0,5 mm; - 2,5 mm; - 5 mm; - 7,5 mm and - 10 mm.

E FIELD PROBES optionally RF or XF FREQUENCY RANGE 30 MHz up to 6 GHz

Application	Description	Characteristic
	**RF-E 04** Frequency range: **30 MHz to 3 GHz** Electrode surface area: approx. 5 x 5 mm Connection: SMB - can be used to inject RF	
	**RF-E 09** Frequency range: **30 MHz to 3 GHz** Electrode surface area: approx. 10 x 10 mm Connection: SMB - can be used to inject RF	
	**XF-E 04** Frequency range: **30 MHz to 6 GHz** Electrode surface area: approx. 5 x 5 mm Connection: SMA	
	**XF-E 09** Frequency range: **30 MHz to 6 GHz** Electrode surface area: approx. 10 x 10 mm Connection: SMA	

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